 Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination
10/754,501	LEE ET AL.
Examiner	Art Unit
Long Nauven	2816

	SEAR	CHED	
Class	Subclass	Date	Examiner
327	333,427,68,70,		LN
316	198,544		-
365	189-11	\	1
upalat	isove	8/M05	in

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
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